

Description

These N-Channel enhancement mode power field effect transistors are using split gate trench DMOS technology. This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficiency fast switching applications.

Features

- ◆ 80V, 91A, $R_{DS(on),max} = 6m\Omega @ V_{GS} = 10V$
- ◆ Improved dv/dt capability
- ◆ Fast switching
- ◆ 100% EAS Guaranteed
- ◆ Green device available

Applications

- ◆ Motor Drives
- ◆ UPS
- ◆ DC-DC Converter

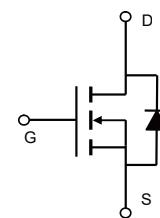
Product Summary

V_{DSS}	80V
$R_{DS(on),max} @ V_{GS}=10V$	$6m\Omega$
I_D	91A

Pin Configuration



TO-263



Schematic

Absolute Maximum Ratings

 $T_C = 25^\circ C$ unless otherwise noted

Parameter	Symbol	Value	Unit
Drain-Source Voltage	V_{DSS}	80	V
Continuous drain current ($T_C = 25^\circ C$)	I_D	91	A
($T_C = 100^\circ C$)		62	A
Pulsed drain current ¹⁾	I_{DM}	273	A
Gate-Source voltage	V_{GSS}	± 20	V
Avalanche energy ²⁾	E_{AS}	7.2	mJ
Power Dissipation	P_D	89	W
Storage Temperature Range	T_{STG}	-55 to +150	°C
Operating Junction Temperature Range	T_J	-55 to +150	°C

Thermal Characteristics

Parameter	Symbol	Value	Unit
Thermal Resistance, Junction-to-Case	$R_{\theta JC}$	1.4	°C/W
Thermal Resistance Junction-to-Ambient	$R_{\theta JA}$	62	°C/W

Package Marking and Ordering Information

Device	Device Package	Marking	Units/Reel
VST08N060-T3	TO-263	VST08N060-T3	800

Electrical Characteristics

T_J = 25°C unless otherwise noted

Parameter	Symbol	Test Condition	Min.	Typ.	Max.	Unit
Static characteristics						
Drain-source breakdown voltage	BV _{DSS}	V _{GS} =0 V, I _D =250μA	80	---	---	V
Gate threshold voltage	V _{GS(th)}	V _{DS} =V _{GS} , I _D =250μA	1.2	1.7	2.5	V
Drain-source leakage current	I _{DSS}	V _{DS} =80 V, V _{GS} =0V	---	---	1	μA
Gate leakage current, Forward	I _{GSSF}	V _{GS} =20 V, V _{DS} =0 V	---	---	100	nA
Gate leakage current, Reverse	I _{GSSR}	V _{GS} =-20 V, V _{DS} =0 V	---	---	-100	nA
Drain-source on-state resistance	R _{DS(on)}	V _{GS} =10 V, I _D =20 A	---	4.6	6	mΩ
		V _{GS} =4.5 V, I _D =20 A	---	6.3	8.5	mΩ
Forward transconductance	g _f	V _{DS} =5V , I _D =20A	---	76	---	S
Dynamic characteristics						
Input capacitance	C _{iss}	V _{DS} = 40 V, V _{GS} = 0 V, F = 1MHz	---	2862	---	pF
Output capacitance	C _{oss}		---	412	---	
Reverse transfer capacitance	C _{rss}		---	36	---	
Turn-on delay time	t _{d(on)}	V _{DD} = 40V, V _{GS} =10V, I _D = 20A R _G =3.3Ω	---	8.1	---	ns
Rise time	t _r		---	4.2	---	
Turn-off delay time	t _{d(off)}		---	36.3	---	
Fall time	t _f		---	7.0	---	
Gate resistance	R _g	V _{GS} =0 V,V _{DS} =0 V, F=1MHz	---	0.5	---	Ω
Gate charge characteristics						
Gate to source charge	Q _{gs}	V _{DS} =40V, I _D =20A, V _{GS} = 10 V	---	7.1	---	nC
Gate to drain charge	Q _{gd}		---	6.6	---	
Gate charge total	Q _g		---	46	---	
Drain-Source diode characteristics and Maximum Ratings						
Continuous Source Current	I _s	V _{GS} =0V, I _s =20A, T _J =25°C	---	---	74	A
Pulsed Source Current ³⁾	I _{SM}		---	---	223	A
Diode Forward Voltage	V _{SD}	V _{GS} =0V, I _s =20A, T _J =25°C	---	---	1.2	V

Notes:

1: Repetitive Rating: Pulse width limited by maximum junction temperature.

2: V_{DD}=25V, V_{GS}=10V, L=0.1mH, I_{AS}=12A, Starting T_J=25°C.

3: Pulse Test: Pulse Width ≤300 μ s, Duty Cycle≤2%.

Electrical Characteristics Diagrams

Figure 1. Typ. Output Characteristics

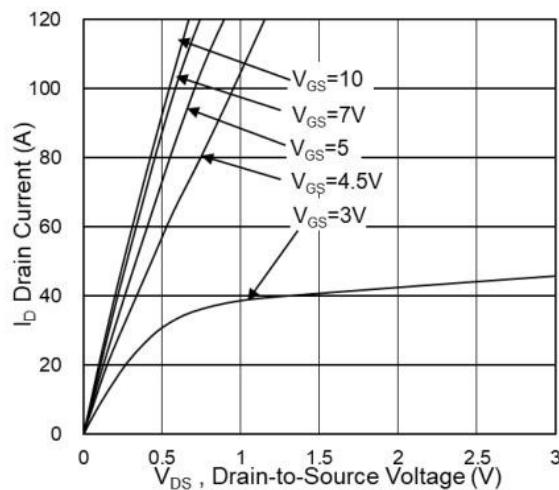


Figure 3. Capacitance Characteristics

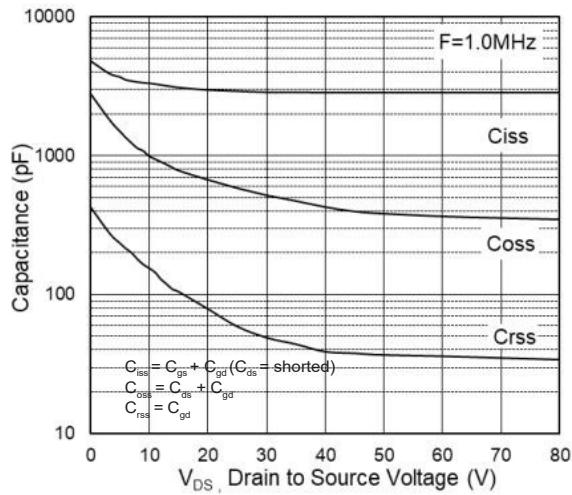


Figure 5. Body-Diode Characteristics

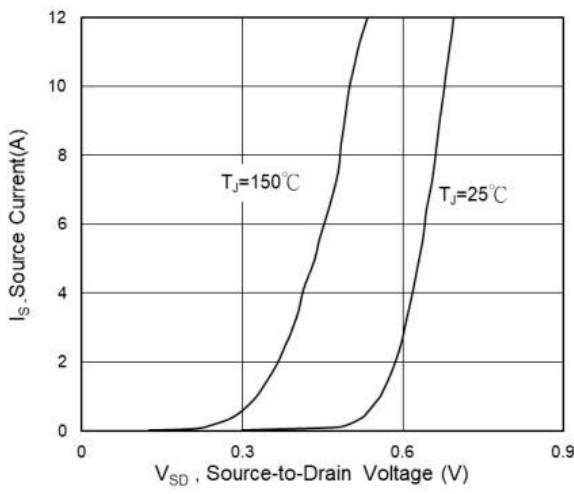


Figure 2. Transfer Characteristics

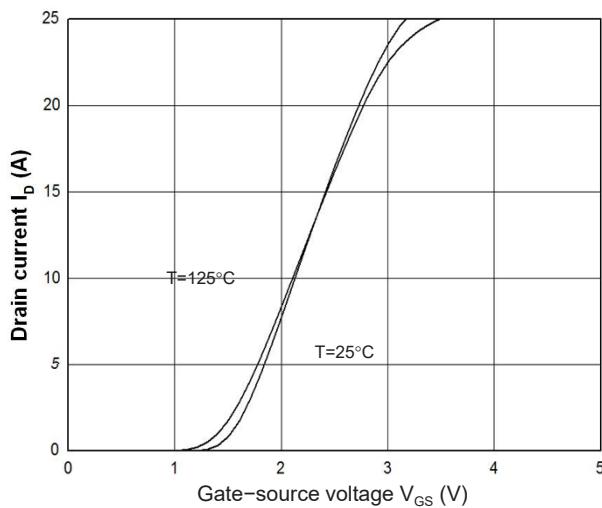


Figure 4. Gate Charge Waveform

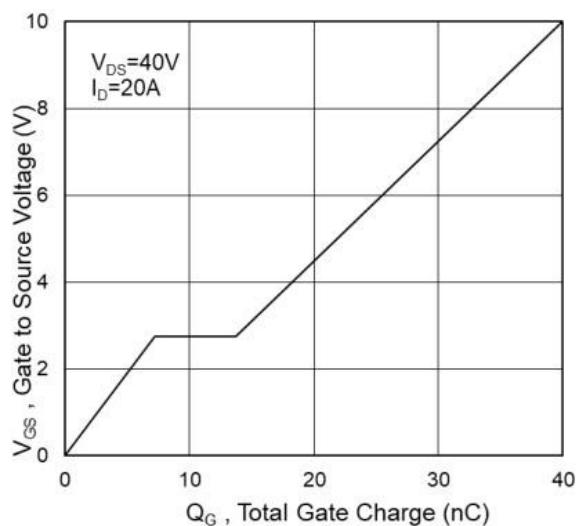


Figure 6. Rdson-Drain Current

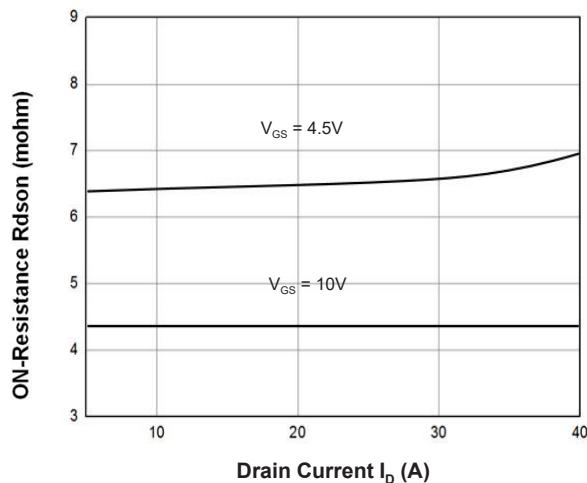


Figure 7. Rdson-Junction Temperature

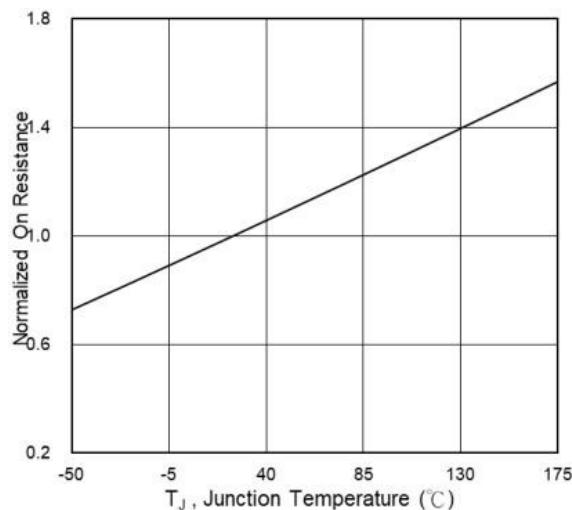


Figure 8. $V_{GS(th)}$ -Junction Temperature

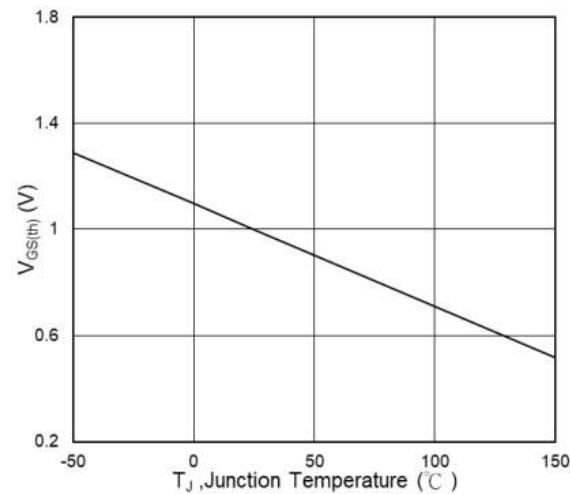


Figure 9. On-Resistance vs. Gate-to-Source voltage

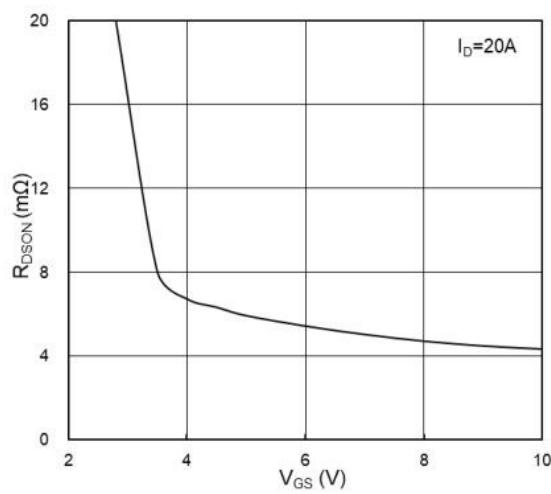


Figure 10: Safe Operating Area

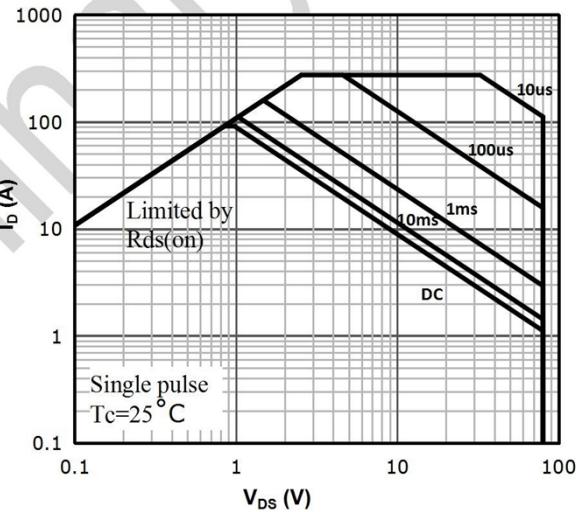
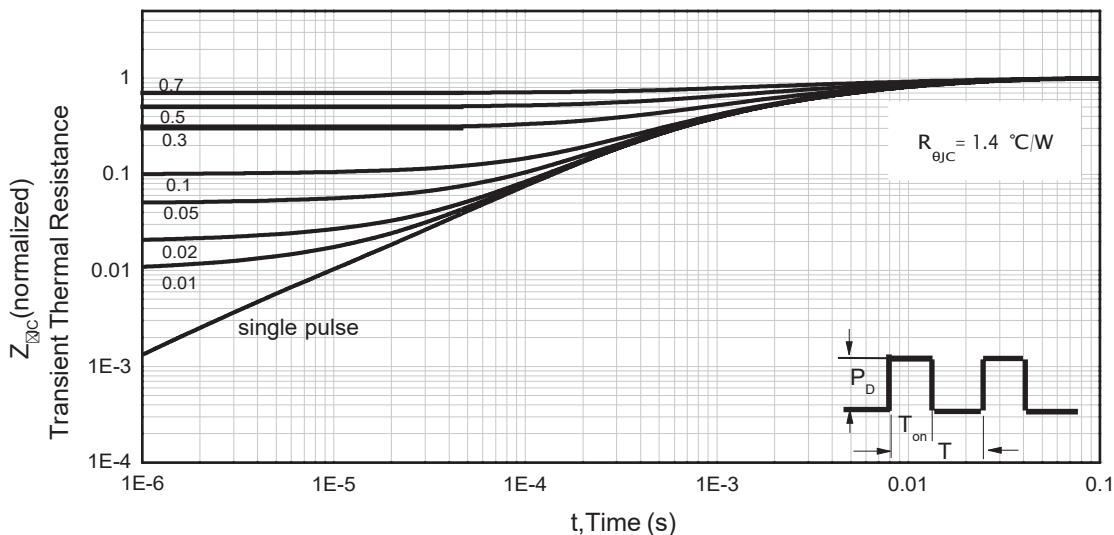
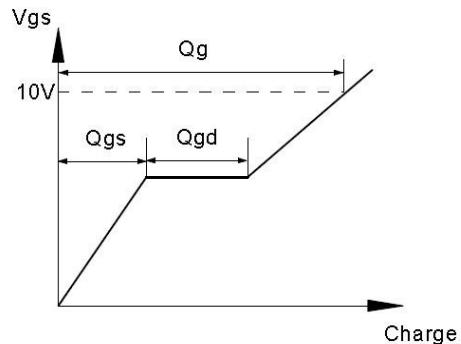
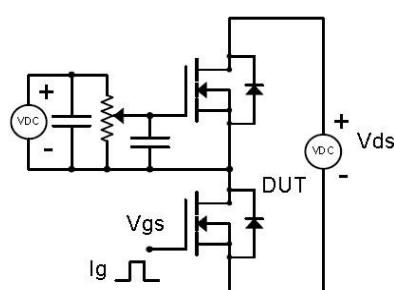


Figure 11. Normalized Maximum Transient Thermal Impedance (R_{thJC})

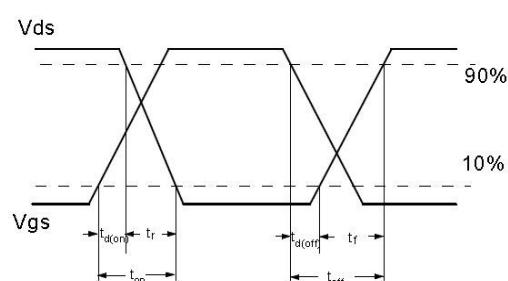
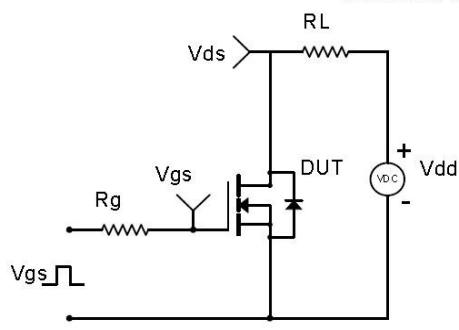


Test Circuit & Waveform

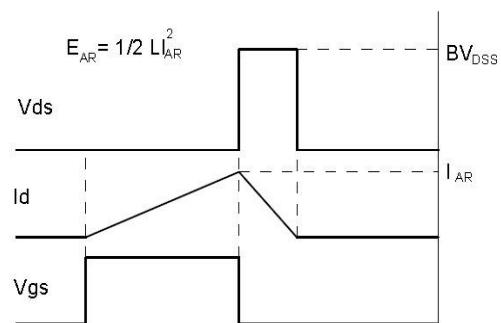
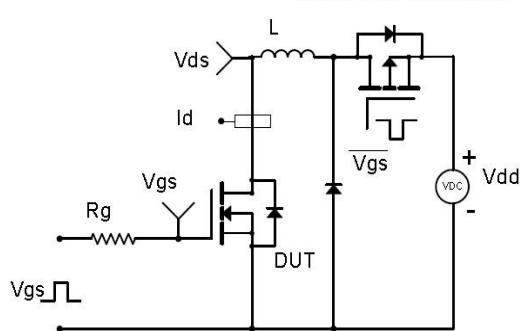
Gate Charge Test Circuit & Waveform



Resistive Switching Test Circuit & Waveforms



Unclamped Inductive Switching (UIS) Test Circuit & Waveforms



Diode Recovery Test Circuit & Waveforms

